

PolarHV[™] HiPerFET Power MOSFET

IXFA 16N50P IXFH 16N50P IXFP 16N50P

N-Channel Enhancement Mode Avalanche Rated Fast Intrinsic Diode

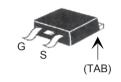


V _{DSS}	=	500	V
I _{D25}	=	16	Α
R _{DS(on)}	≤	400	$m\Omega$
t _{rr}	≤	200	ns

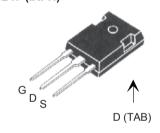
Symbol	Test Conditions	Maximum	Ratings
V _{DSS}	$T_J = 25^{\circ} \text{ C to } 150^{\circ} \text{ C}$	500	V
V _{DGR}	$T_J = 25^{\circ} \text{ C to } 150^{\circ} \text{ C}; R_{GS} = 1 \text{ M}\Omega$	500	V
V _{GS}	Continuous	±30) V
V _{GSM}	Transient	±40	V
I _{D25}	$T_{_{\rm C}}$ = 25° C	16	A
I _{DM}	$T_{_{\rm C}}$ = 25° C, pulse width limited by $T_{_{\rm JM}}$	35	A
I _{AR}	T _c = 25° C	16	A
E _{AR}	T _c = 25° C	25	mJ
E _{AS}	T _c = 25° C	750	mJ
dv/dt	$I_{_{\mathrm{S}}} \leq I_{_{\mathrm{DM}}}, \ \mathrm{di/dt} \leq 100 \ \mathrm{A/\mu s}, \ V_{_{\mathrm{DD}}} \leq V_{_{\mathrm{DSS}}}, \ T_{_{\mathrm{J}}} \leq 150^{\circ} \mathrm{C}, \ R_{_{\mathrm{G}}} = 10 \ \Omega$	10	V/ns
P_{D}	T _C =25°C	300	W
T _J		-55 +150	°C
T _{JM}		150	°C
T _{stg}		-55 +150	°C
T _L T _{SOLD}	1.6 mm (0.062 in.) from case for 10 s Plastic body for 10 s soldering	300 260	°C
M _d	Mounting torque (TO-247 & TO-220)	1.13/10	Nm/lb.in.
Weight	TO-220	4	g
	TO-263	3	g
	TO-247	5.5	g

Symbol (T _J = 25° C, t	Test Conditions unless otherwise specified)		Ch Min.	istic Val	
BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		500		V
V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 2.5 \text{ mA}$		3.0	5.5	V
GSS	$V_{GS} = \pm 30 V_{DC}, V_{DS} = 0$			±100	nA
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 125° C		5 250	μ Α μ Α
R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 0.5 I_{D25}$ Pulse test, t ≤300 µs, duty	cycle d ≤ 2 %		400	mΩ

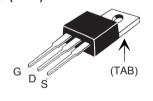
TO-263 (IXTA)



TO-247 (IXFH)



TO-220 (IXTP)



G = Gate D = DrainS = Source TAB = Drain

Features

- ¹ International standard packages
- Unclamped Inductive Switching (UIS) rated
- ¹ Low package inductance
 - easy to drive and to protect

Advantages

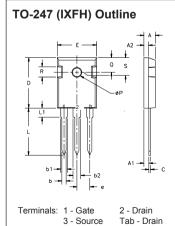
- Easy to mount
- Space savings
- High power density



Symbo	ol	Test Conditions $(T_{\perp} = 25^{\circ} \text{ C, un})$			ristic Values
		Mir		Typ.	Max.
g_{fs}		$V_{DS} = 20 \text{ V}; I_{D} = 0.5 I_{D25}, \text{ pulse test}$	3	16	S
\mathbf{C}_{iss})			2250	pF
Coss	}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		240	pF
C _{rss}	J			12	pF
t _{d(on)})			23	ns
t _r		$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}_{DSS}, I_{D} = I_{D25}$		25	ns
$\mathbf{t}_{d(off)}$		$R_{_{\rm G}}$ = 10 Ω (External)		70	ns
t _f	J			22	ns
$\mathbf{Q}_{g(on)}$)			43	nC
Q_{gs}	}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = 0.5 I_{D25}$		15	nC
\mathbf{Q}_{gd}	J			12	nC
R _{thJC}					0.42° C/W
$\mathbf{R}_{ ext{thCS}}$		(TO-220) (TO-247)		0.25 0.21	° C/W ° C/W

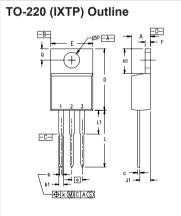
Source-Drain Diode

Symbol	Test Conditions	Min.	Тур.	Max.	
I _s	$V_{GS} = 0 V$			16	Α
I _{SM}	Repetitive			35	Α
$\mathbf{V}_{\mathtt{SD}}$	$I_{_F} = I_{_S}, V_{_{\mathrm{GS}}} = 0 \text{V},$ Pulse test, t \leq 300 µs, duty cycle d \leq 2 %			1.5	V
t _{rr}	$I_F = 16 \text{ A}, -di/dt = 100 \text{ A/}\mu\text{s}$ $V_R = 100 \text{ V}$		130 6	200	ns A
Q_{RM}			0.6		μС



Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
Α	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
С	.4	.8	.016	.031
D	20.80	21.46	.819	.845
Е	15.75	16.26	.610	.640
е	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	242	BSC

TO-263 (IXTA) Outline 1. GATE 2. DPAIN (COLLECTOR) 3. SOURCE (BMTREY) 4. DPAIN (COLLECTOR) 4. DPAIN (COLLECTOR) 5. SYM MIN MAX MIN MAX A J.60 J.90 4.06 4.83 A1 0.80 J.10 2.03 2.79 b 0.20 0.39 0.51 0.99 b 0.20 0.45 0.55 1.14 1.40 c 0.16 0.29 0.40 0.74 c 2 0.45 0.55 1.14 1.40 D 3.40 380 8.64 9.65 D 1 3.15 350 8.00 8.89 E 3.80 4.10 9.65 10.41 E 1 245 3.20 6.22 8.13 e 1.00 BSC 2.54 BSC L 5.75 6.25 14.61 15.88 L 1 0.90 1.10 2.29 2.79 L 2 0.440 0.55 1.02



Pins: 1 - Gate 2 - Drain 3 - Source 4 - Drain

SYM	INCHES		MILLIMETERS	
2114	MIN	MAX	MIN	MAX
Α	.170	.190	4.32	4.83
b	.025	.040	0.64	1.02
b1	.045	.065	1.15	1.65
С	.014	.022	0.35	0.56
D	.580	.630	14.73	16.00
E	.390	.420	9.91	10.66
е	.100	BSC	2.54 BSC	
F	.045	.055	1.14	1.40
H1	.230	.270	5.85	6.85
J1	.090	.110	2.29	2.79
k	0	.015	0	0.38
L	.500	.550	12.70	13.97
L1	.110	.230	2.79	5.84
ØP	.139	.161	3.53	4.08
Q	.100	.125	2.54	3.18

IXYS reserves the right to change limits, test conditions, and dimensions.



Fig. 1. Output Characteristics @ 25°C

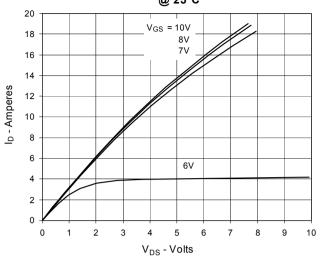


Fig. 2. Output Characteristics

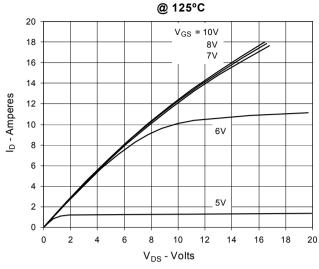


Fig. 3. $R_{DS(on)}$ Normalized to I_D = 8A vs. Junction Temperature

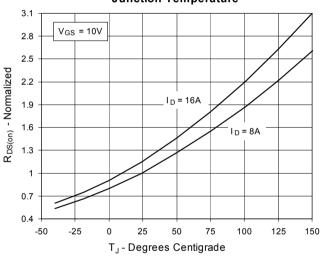


Fig. 4. $R_{DS(on)}$ Normalized to I_D = 8A vs. Drain

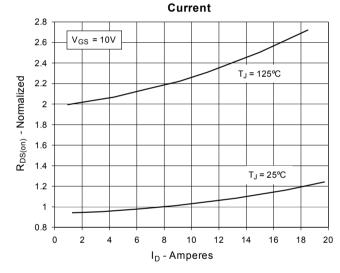


Fig. 5. Maximum Drain Current vs.

Case Temperature

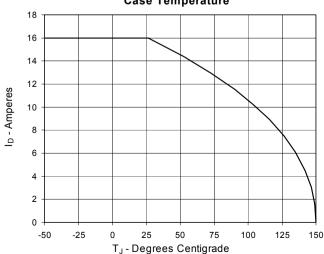
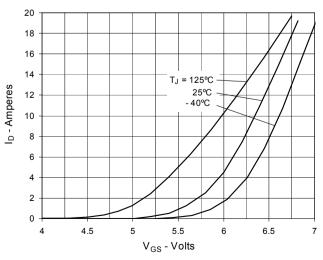


Fig. 6. Input Admittance





4

2

0

2 4

26 24 22 20 18 16 25°C 25°C 125°C 10 00 10 8

10

I_D - Amperes

12

14

16 18

20

Fig. 7. Transconductance

Intrinsic Diode 70 60 50 Is - Amperes 40 30 T_J = 125℃ 20 T_J = 25°C 10 0 0.3 0.4 0.5 0.6 0.7 0.8 0.9 1.2 1.1

V_{SD} - Volts

Fig. 8. Forward Voltage Drop of

Fig. 9. Gate Charge 10 V_{DS} = 250V 9 I_D = 8A 8 I_G = 10mA 7 V_{GS} - Volts 6 4 3 2 1 0 0 5 10 20 25 30 35 40 45 Q_G - NanoCoulombs

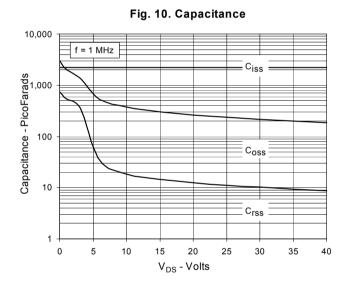
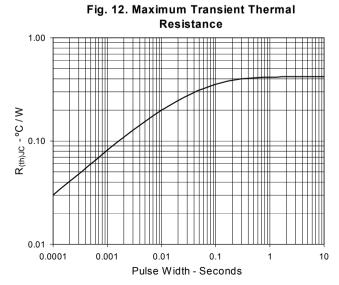


Fig. 11. Forward-Bias Safe Operating Area 100 R_{DS(on)} Limit I_D - Amperes 25µs 100µs 1ms 10m T_J = 150°C DC T_C = 25°C 10 100 1000 V_{DS} - Volts



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